EDFAS FA Workshop

Venue: National University of Singapore, Block E7, #03-08/09, Seminar Room 3/4,
15 Kent Ridge Crescent Singapore 119276

Friday, 17 July 2026

National University of Singapore (NUS) SHINE and EDFAS have jointly organized the inaugural ASEAN Failure Analysis workshop in Singapore with industry collaboration and sponsorship from SEMICAPS. The workshop will bring together leading industry partners, vendors, and academia for a day of activities that introduce, discuss, and share the most cutting-edge advancements in the industry. Following the workshop, there will be a panel discussion with experts, followed by a networking session for engineers, students, and experts.

**Seating is limited, and registration is required for entry. Unfortunately, walk-ins will not be accepted.

**Please RSVP to rsvp@semicaps.com by 8 July 2026. You will receive an email confirmation for registration.

INTRODUCTION

08:45am	09:15hrs	**REGISTRATION**		
09:15am	09:30hrs	**OPENING**	Prof. Lim Yeow Kheng	Introduction: NUS-Shine
			Ms. Rose M. Ring	EDFAS and Workshop Agenda

TECHNICAL PRESENTATIONS

Time Start	**Time End**	
09:30hrs	10:05hrs	
Speaker	Dr. Wen-Hsien Chuang, Technical Director of New Technology Product Infrastructure Division, TSMC	
Topic	The Future of Failure Analysis: Gaps and Strategies for Emerging Semiconductor Innovations	
10:05hrs	10:40hrs	
Speaker	Ms. Susan Li, Technical Director, Marvell Technology	
Topic	Advanced Packaging Overview and Failure Analysis Challenges	
10:40hrs	10:55hrs	**BREAK**
10:55hrs	11:30hrs	
Speaker	Ms. Grace Tan, Director of Engineering/Failure Analysis, Qualcomm/Singapore	
Topic	FA on the Automotive Edge	
11:30hrs	12:05hrs	
Speaker	Dr. Mike Bruce, VP of Applications and Engineering, SEMICAPS	
Topic	EFA Basics, Challenges, Innovations, and Roadmap	
12:05hrs	12:45hrs	**LUNCH**

EDFAS
Electronic Device Failure Analysis Society
ASM INTERNATIONAL

NUS
National University of Singapore
College of Design and Engineering

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TECHNICAL PRESENTATIONS

Time Start	Time End
12:45hrs	13:20hrs
Speaker	Mr. Benny Hsu, Senior Device Analysis Engineer, AMD/USA
Topic	From Monolithic to Chiplet to Module: The New Frontier of Fault Isolation
13:20hrs	13:55hrs
Speaker	Professor Jeroen Anton Van Kan, Founder of Anoton Technology, National University of Singapore
Topic	Proton Microscopy for Advanced Semiconductor Failure Analysis and Subsurface Characterization
13:55hrs	14:25hrs
Speaker	Dr. Joseph Liao, Founder and Chief Technology Officer, EnliTech
Topic	Spectral Imaging–Based Optical Loss Mapping for Efficient Failure Analysis and Wafer-Level Screening of Silicon Photonic Integrated
14:25hrs	14:55hrs
Speaker	Dr. Marc Heinemann, Team Leader/Failure Analysis, SmarAct Metrology
Topic	Nanoprobing for Defect Localization
14:55hrs	15:25hrs
Speaker	Mr. Greg Johnson, Senior Applications Development Engineer, Zeiss
Topic	SEM Passive Voltage Contrast

15:25hrs 15:40hrs **BREAK**

15:40hrs 16:40hrs

PANEL DISCUSSION

Moderator: Prof. Lim Yeow Kheng

Panelists

Dr. Wen-Hsien Chuang, TSMC

Ms. Grace Tan, Qualcomm

Dr. Mike Bruce, SEMICAPS

Prof. Jeroen Anton Van Kan, NUS

Panel Title: Closing the Failure Analysis Gap for the AI-Era Semiconductor Industry

Perspectives

Foundry perspective on advanced semiconductor technology trends and emerging failure analysis gaps

Automotive and application-driven reliability, with a focus on failure analysis challenges

Electrical failure analysis and FA tool development roadmap

Advanced characterization techniques and academic research capabilities

16:40hrs 17:00hrs **FINALE**

17:00hrs 18:00hrs **NETWORKING**

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